Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/712,788	DELMULLE ET AL.	
Examiner	Art Unit	
Yuwen Pan	2618	

SEARCHED					
Class	Subclass	Date	Examiner		
455	41.2,41.3, 550.1 552.1	5/6/2006	ΥP		
	556.1				
	557				
	559				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
		-			
	<u> </u>				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST(USPG-PUB,USPAT)	5/6/2006	YP		